# 3.3 V, 1.5 Gb/s Dual AnyLevel<sup>TM</sup> to LVDS Receiver/Driver/Buffer/Translator

## **Description**

NB4N855S is a clock or data Receiver/Driver/Buffer/Translator capable of translating AnyLevel<sup>TM</sup> input signal (LVPECL, CML, HSTL, LVDS, or LVTTL/LVCMOS) to LVDS. Depending on the distance, noise immunity of the system design, and transmission line media, this device will receive, drive or translate data or clock signals up to 1.5 Gb/s or 1.0 GHz, respectively. This device is pin–for–pin plug in compatible to the SY55855V in a 3.3 V applications.

The NB4N855S has a wide input common mode range of GND + 50 mV to  $V_{CC}-50$  mV. This feature is ideal for translating differential or single–ended data or clock signals to 350 mV typical LVDS output levels.

The device is offered in a small 10 lead MSOP package. NB4N855S is targeted for data, wireless and telecom applications as well as high speed logic interface where jitter and package size are main requirements.

Application notes, models, and support documentation are available at www.onsemi.com.

#### **Features**

- Guaranteed Input Clock Frequency up to 1.0 GHz
- Guaranteed Input Data Rate up to 1.5 Gb/s
- 490 ps Maximum Propagation Delay
- 1.0 ps Maximum RMS Jitter
- 180 ps Maximum Rise/Fall Times
- Single Power Supply;  $V_{CC} = 3.3 \text{ V} \pm 10\%$
- Temperature Compensated TIA/EIA-644 Compliant LVDS Outputs
- GND + 50 mV to  $V_{CC}$  50 mV  $V_{CMR}$  Range

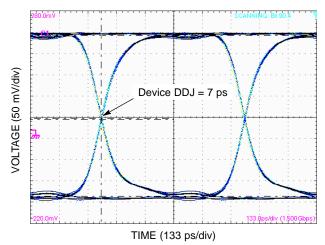


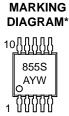
Figure 1. Typical Output Waveform at 1.5 Gb/s with K28.5 (V<sub>INPP</sub> = 100 mV, Input Signal DDJ = 24 ps)



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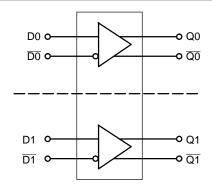




A = Assembly Location Y = Year

Y = Year W = Work Week

\*For additional marking information, refer to Application Note AND8002/D.



## **Functional Block Diagram**

#### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 8 of this data sheet.

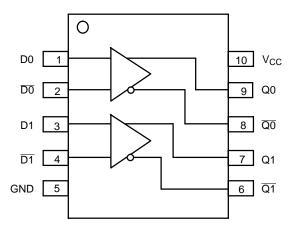


Figure 2. Pin Configuration and Block Diagram (Top View)

# **Table 1. PIN DESCRIPTION**

| Pin | Name            | I/O                                 | Description  |
|-----|-----------------|-------------------------------------|--|
| 1   | D0              | LVPECL, CML, LVCMOS,<br>LVTTL, LVDS | Noninverted Differential Clock/Data D0 Input.  |
| 2   | D0              | LVPECL, CML, LVCMOS,<br>LVTTL, LVDS | Inverted Differential Clock/Data $\overline{D0}$ Input.  |
| 3   | D1              | LVPEL, CML, LVDS LVCMOS,<br>LVTTL   | Noninverted Differential Clock/Data D1 Input.  |
| 4   | D1              | LVPECL, CML, LVDS<br>LVCMOS LVTTL   | Inverted Differential Clock/Data D1 Input.   |
| 5   | GND             | -                                   | Ground. 0 V.   |
| 6   | Q1              | LVDS Output                         | Inverted $\overline{\text{Q1}}$ output. Typically loaded with 100 $\Omega$ receiver termination resistor across differential pair. |
| 7   | Q1              | LVDS Output                         | Noninverted Q1 output. Typically loaded with 100 $\Omega$ receiver termination resistor across differential pair.                  |
| 8   | Q0              | LVDS Output                         | Inverted $\overline{Q0}$ output. Typically loaded with 100 $\Omega$ receiver termination resistor across differential pair.        |
| 9   | Q0              | LVDS Output                         | Noninverted Q0 output. Typically loaded with 100 $\Omega$ receiver termination resistor across differential pair.                  |
| 10  | V <sub>CC</sub> | -                                   | Positive Supply Voltage.   |

**Table 2. ATTRIBUTES** 

| Charac                        | Value   |                             |
|-------------------------------|---|-----------------------------|
| Moisture Sensitivity (Note 1) | Level 1   |                             |
| Flammability Rating           | Oxygen Index: 28 to 34                                    | UL 94 V-0 @ 0.125 in        |
| ESD Protection                | Human Body Model<br>Machine Model<br>Charged Device Model | > 2 kV<br>> 200 V<br>> 1 kV |
| Transistor Count              | 281   |                             |
| Meets or exceeds JEDEC Spe    |   |                             |

<sup>1.</sup> For additional information, see Application Note AND8003/D.

**Table 3. MAXIMUM RATINGS** 

| Symbol            | Parameter   | Condition 1                      | Condition 2              | Rating      | Unit     |
|-------------------|---|----------------------------------|--------------------------|-------------|----------|
| V <sub>CC</sub>   | Positive Power Supply   | GND = 0 V                        |                          | 3.8         | V        |
| VI                | Positive Input  | GND = 0 V                        | $V_I = V_{CC}$           | 3.8         | V        |
| I <sub>IN</sub>   | Input Current Through R <sub>T</sub> (50 Ω Resistor)  | Static<br>Surge                  |                          | 35<br>70    | mA<br>mA |
| losc              | Output Short Circuit Current Line-to-Line (Q to $\overline{\mathbb{Q}}$ ) Line-to-End (Q or $\overline{\mathbb{Q}}$ to GND) | Q or Q to GND<br>Q to Q          | Continuous<br>Continuous | 12<br>24    | mA       |
| T <sub>A</sub>    | Operating Temperature Range   | Micro 10                         |                          | -40 to +85  | °C       |
| T <sub>stg</sub>  | Storage Temperature Range   |                                  |                          | -65 to +150 | °C       |
| $\theta_{JA}$     | Thermal Resistance (Junction-to-Ambient) (Note 2)   | 0 lfpm<br>500 lfpm               | Micro 10<br>Micro 10     | 177<br>132  | °C/W     |
| $\theta_{\sf JC}$ | Thermal Resistance (Junction-to-Case)   | 1S2P (Note 4)                    | Micro 10                 | 40          | °C/W     |
| T <sub>sol</sub>  | Wave Solder Pb Pb-Free  | <3 Sec @ 248°C<br><3 Sec @ 260°C |                          | 265<br>265  | °C       |

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

2. JEDEC standard multilayer board – 1S2P (1 signal, 2 power).

Table 4. DC CHARACTERISTICS, CLOCK INPUTS, LVDS OUTPUTS  $V_{CC} = 3.0 \text{ V}$  to 3.6 V, GND = 0 V,  $T_A = -40 ^{\circ}\text{C}$  to  $+85 ^{\circ}\text{C}$ 

| Symbol           | Characteristic  | Min                   | Тур  | Max                   | Unit |
|------------------|---|-----------------------|------|-----------------------|------|
| I <sub>CC</sub>  | Power Supply Current (Note 3)   |                       | 40   | 53                    | mA   |
| DIFFERE          | NTIAL INPUTS DRIVEN SINGLE-ENDED (Figures 10 and 12)                            | 1                     |      | •                     |      |
| V <sub>th</sub>  | Input Threshold Reference Voltage Range (Note 4)                                | GND +100              |      | V <sub>CC</sub> – 100 | mV   |
| V <sub>IH</sub>  | Single-ended Input HIGH Voltage   | V <sub>th</sub> + 100 |      | V <sub>CC</sub>       | mV   |
| V <sub>IL</sub>  | Single-ended Input LOW Voltage  | GND                   |      | V <sub>th</sub> – 100 | mV   |
| DIFFERE          | NTIAL INPUTS DRIVEN DIFFERENTIALLY (Figures 11 and 13)                          |                       |      |                       |      |
| V <sub>IHD</sub> | Differential Input HIGH Voltage   | 100                   |      | V <sub>CC</sub>       | mV   |
| V <sub>ILD</sub> | Differential Input LOW Voltage  | GND                   |      | V <sub>CC</sub> – 100 | mV   |
| V <sub>CMR</sub> | Input Common Mode Range (Differential Configuration)                            | GND + 50              |      | V <sub>CC</sub> - 50  | mV   |
| V <sub>ID</sub>  | Differential Input Voltage (V <sub>IHD</sub> – V <sub>ILD</sub> )               | 100                   |      | V <sub>CC</sub>       | mV   |
| LVDS OL          | ITPUTS (Note 5)   |                       |      |                       |      |
| V <sub>OD</sub>  | Differential Output Voltage   | 250                   |      | 450                   | mV   |
| $\Delta V_{OD}$  | Change in Magnitude of V <sub>OD</sub> for Complimentary Output States (Note 6) | 0                     | 1.0  | 25                    | mV   |
| Vos              | Offset Voltage (Figure 9)   | 1125                  |      | 1375                  | mV   |
| $\Delta V_{OS}$  | Change in Magnitude of V <sub>OS</sub> for Complimentary Output States (Note 6) | 0                     | 1.0  | 25                    | mV   |
| V <sub>OH</sub>  | Output HIGH Voltage (Note 7)  |                       | 1425 | 1600                  | mV   |
| V <sub>OL</sub>  | Output LOW Voltage (Note 8)   | 900                   | 1075 |                       | mV   |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- 3.  $Dx/\overline{Dx}$  at the DC level within  $V_{CMR}$  and output pins loaded with  $R_L$  = 100  $\Omega$  across differential.
- 4. V<sub>th</sub> is applied to the complementary input when operating in single–ended mode.
- 5. LVDS outputs require 100  $\Omega$  receiver termination resistor between differential pair. See Figure 8.
- Parameter guaranteed by design verification not tested in production.
   V<sub>OH</sub>max = V<sub>OS</sub>max + ½ V<sub>OD</sub>max.
   V<sub>OL</sub>max = V<sub>OS</sub>min ½ V<sub>OD</sub>max.

Table 5. AC CHARACTERISTICS  $V_{CC} = 3.0 \text{ V}$  to 3.6 V, GND = 0 V; (Note 9)

|  |  | -40°C      |                                  | 25°C                           |            | 85°C                             |                                |            |                                  |                                |      |
|--|--|------------|----------------------------------|--------------------------------|------------|----------------------------------|--------------------------------|------------|----------------------------------|--------------------------------|------|
| Symbol                                 | Characteristic   | Min        | Тур                              | Max                            | Min        | Тур                              | Max                            | Min        | Тур                              | Max                            | Unit |
| V <sub>OUTPP</sub>                     | Output Voltage Amplitude (@ $V_{INPPMIN}$ ) $f_{in} \le 1.0 \; GHz$ (Figure 3) $f_{in} = 1.5 \; GHz$   | 230<br>200 | 350<br>300                       |                                | 230<br>200 | 350<br>300                       |                                | 230<br>200 | 350<br>300                       |                                | mV   |
| f <sub>DATA</sub>                      | Maximum Operating Data Rate  | 1.5        | 2.5                              |                                | 1.5        | 2.5                              |                                | 1.5        | 2.5                              |                                | Gb/s |
| t <sub>PLH</sub> ,<br>t <sub>PHL</sub> | Differential Input to Differential Output<br>Propagation Delay   | 330        | 410                              | 490                            | 330        | 410                              | 490                            | 330        | 410                              | 490                            | ps   |
| t <sub>SKEW</sub>                      | Duty Cycle Skew (Note 10) Within –Device Skew (Note 11) Device to Device Skew (Note 12)  |            | 8<br>10<br>20                    | 45<br>35<br>100                |            | 8<br>10<br>20                    | 45<br>35<br>100                |            | 8<br>10<br>20                    | 45<br>35<br>100                | ps   |
| <b>UITTER</b>                          | RMS Random Clock Jitter (Note 13) $ \begin{aligned} & f_{in} = 1.0 \text{ GHz} \\ & f_{in} = 1.5 \text{ GHz} \end{aligned} $ Deterministic Jitter (Note 14) $ \begin{aligned} & f_{DATA} = 622 \text{ Mb/s} \\ & f_{DATA} = 1.5 \text{ Gb/s} \\ & f_{DATA} = 2.488 \text{ Gb/s} \end{aligned} $ Crosstalk Induced Jitter (Note 15) |            | 0.5<br>0.5<br>6<br>7<br>10<br>20 | 1<br>1<br>15<br>20<br>25<br>40 |            | 0.5<br>0.5<br>6<br>7<br>10<br>20 | 1<br>1<br>15<br>20<br>25<br>40 |            | 0.5<br>0.5<br>6<br>7<br>10<br>20 | 1<br>1<br>15<br>20<br>25<br>40 | ps   |
| V <sub>INPP</sub>                      | Input Voltage Swing/Sensitivity (Differential Configuration) (Note 16)   | 100        |                                  | V <sub>CC</sub> -<br>GND       | 100        |                                  | V <sub>CC</sub> -<br>GND       | 100        |                                  | V <sub>CC</sub> -<br>GND       | mV   |
| t <sub>r</sub><br>t <sub>f</sub>       | Output Rise/Fall Times @ 250 MHz $$ Q, $\overline{Q}$ (20% – 80%)  | 50         | 110                              | 180                            | 50         | 110                              | 180                            | 50         | 110                              | 180                            | ps   |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- 9. Measured by forcing  $V_{INPPMIN}$  with 50% duty cycle clock source and  $V_{CC}$  1400 mV offset. All loading with an external  $R_L$  = 100  $\Omega$  across "D" and " $\overline{D}$ " of the receiver. Input edge rates 150 ps (20%–80%).
- 10. See Figure 7 differential measurement of t<sub>skew</sub> = |t<sub>PLH</sub> t<sub>PHL</sub>| for a nominal 50% differential clock input waveform @ 250 MHz. 11. The worst case condition between Q0/Q0 and Q1/Q1 from either D0/D0 or D1/D1, when both outputs have the same transition.
- 12. Skew is measured between outputs under identical transition @ 250 MHz.
- 13. RMS jitter with 50% Duty Cycle clock signal.
- 14. Deterministic jitter with input NRZ data at PRBS 2<sup>23</sup>–1 and K28.5.
- 15. Crosstalk Induced Jitter is the additive Deterministic jitter to channel one with channel two active both running at 622 Gb/s PRBS 223 -1 as an asynchronous signals.
- 16. Input voltage swing is a single-ended measurement operating in differential mode.

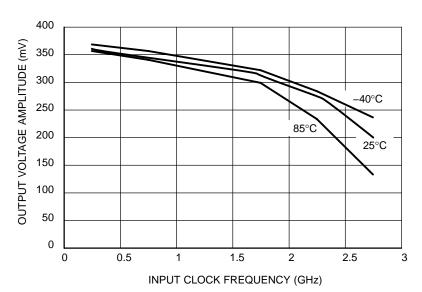


Figure 3. Output Voltage Amplitude ( $V_{OUTPP}$ ) versus Input Clock Frequency ( $f_{in}$ ) and Temperature (@  $V_{CC}$  = 3.3 V)

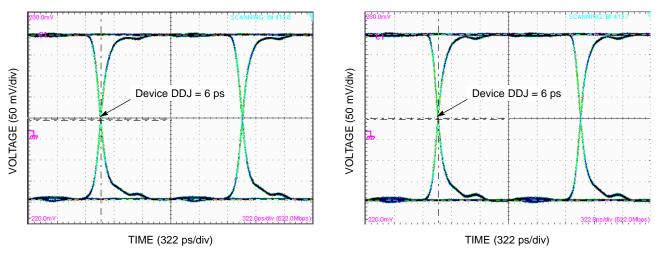


Figure 4. Typical Output Waveform at 1.5 Gb/s with  $2^{23-1}$  (V<sub>INPP</sub> = 100 mV (left) & V<sub>INPP</sub> = 400 mV (right), Input Signal DDJ = 24 ps)

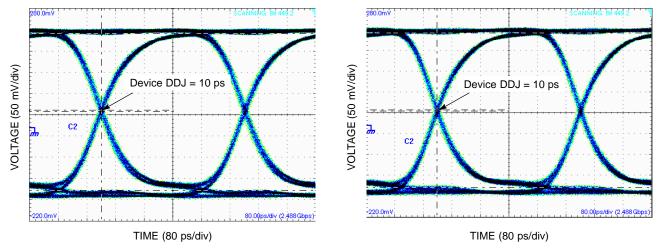


Figure 5. Typical Output Waveform at 2.488 Gb/s with  $2^{23-1}$  (V<sub>INPP</sub> = 100 mV (left) & V<sub>INPP</sub> = 400 mV (right), Input Signal DDJ = 30 ps)

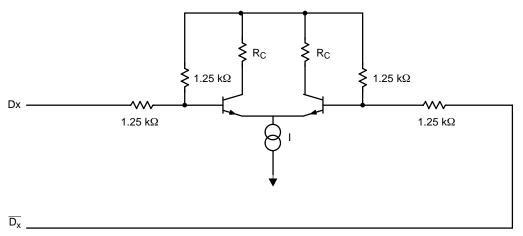


Figure 6. Input Structure

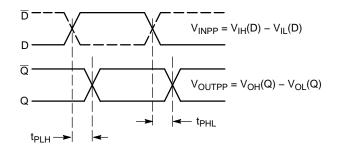


Figure 7. AC Reference Measurement

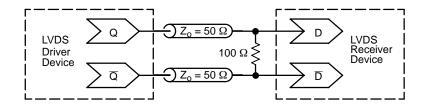


Figure 8. Typical LVDS Termination for Output Driver and Device Evaluation

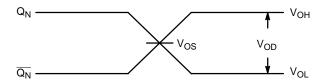


Figure 9. LVDS Output

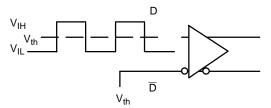


Figure 10. Differential Input Driven Single-Ended

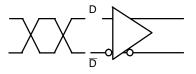


Figure 11. Differential Inputs Driven Differentially

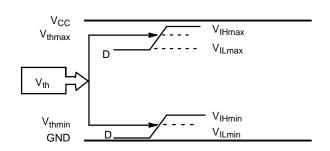


Figure 12. V<sub>th</sub> Diagram

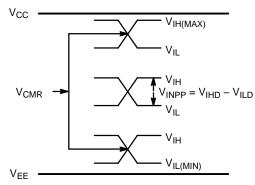


Figure 13. V<sub>CMR</sub> Diagram

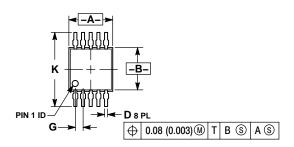
## **ORDERING INFORMATION**

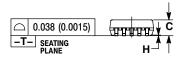
| Device       | Package               | Shipping <sup>†</sup> 1000 / Tape & Reel |  |  |
|--------------|-----------------------|--|--|--|
| NB4N855SMR4  | Micro 10              |  |  |  |
| NB4N855SMR4G | Micro 10<br>(Pb-Free) | 1000 / Tape & Reel                       |  |  |

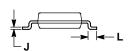
<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

## Micro10 CASE 846B-03 ISSUE D







#### NOTES:

- NOTES:

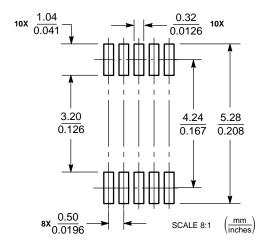
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

  2. CONTROLLING DIMENSION: MILLIMETER.

  3. DIMENSION 'A" DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE
- BURRS SHALL NOT EXCEED 0.15 (0.006)
  PER SIDE.
  DIMENSION "B" DOES NOT INCLUDE
  INTERLEAD FLASH OR PROTRUSION.
  INTERLEAD FLASH OR PROTRUSION
  SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
  846B-01 OBSOLETE. NEW STANDARD
  846B-02

|     | MILLIN | IETERS | INCHES    |       |  |  |
|-----|--------|--------|-----------|-------|--|--|
| DIM | MIN    | MAX    | MIN       | MAX   |  |  |
| Α   | 2.90   | 3.10   | 0.114     | 0.122 |  |  |
| В   | 2.90   | 3.10   | 0.114     | 0.122 |  |  |
| С   | 0.95   | 1.10   | 0.037     | 0.043 |  |  |
| D   | 0.20   | 0.30   | 0.008     | 0.012 |  |  |
| G   | 0.50   | BSC    | 0.020 BSC |       |  |  |
| Н   | 0.05   | 0.15   | 0.002     | 0.006 |  |  |
| J   | 0.10   | 0.21   | 0.004     | 0.008 |  |  |
| K   | 4.75   | 5.05   | 0.187     | 0.199 |  |  |
| L   | 0.40   | 0.70   | 0.016     | 0.028 |  |  |

## **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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